

## 3.0 $\mu$ m N-Well CMOS Process

### Standard Features

- ❖ UTIX Stepper
- ❖ Single or double poly
- ❖ Single or double metal
- ❖ 5.5V max operating voltage

### Process Technology

- ❖ EPI starting material provides latch-up protection

### Process Options

- ❖ Poly 2 (Cap Top Plate)
- ❖ Isolated N-P-N
- ❖ 12V max operation with N-Ldd
- ❖ Low TC SiCr Resistor
- ❖ P & E 760 aligner for large die

### Standard Layout Rules and Process Parameters

	Value	Units
Min gate length (N&P)	3.0	$\mu$ m
Gate oxide	500	Å
Inter-poly dielectric	700	Å
Active (width/space)	4.0/3.0	$\mu$ m
Poly 1 (width/space)	3.0/3.0	$\mu$ m
Poly 2 (width/space)	3.0/3.0	$\mu$ m
Contact (width/space)	3.0/3.0	$\mu$ m
Via (width/space)	3.0/3.0	$\mu$ m
Metal 1 (width/space)	4.0/3.0	$\mu$ m
Metal 2 (width/space)	4.0/4.0	$\mu$ m

### Process Option Parameters

- ❖ N-Ldd N-ch for 10V operation, (12V maximum)  
Min L=4 $\mu$ m (High voltage device has lower drive due to increase in SD resistance. Contact factory for details.)
- ❖ Low TC SiCr resistor: 500+/-100  $\Omega$ /square
- ❖ N-P-N parameters:

Unit	Value
Beta	180
Early Voltage	50V min
BVceo	25V min
BVebo	8.2V

### Typical Electrical Parameters

	N-CH	P-CH	Units
Vt(30X2.0 $\mu$ )	0.8	-0.8	V
Ids	0.09	-0.045	mA/ $\mu$ m
Gain $\mu$ C (30X30)	42	14	$\mu$ A/V <sup>2</sup>
Body Effect	0.3	0.42	V <sup>1/2</sup>
Sub-threshold slope	100	100	mV/decade
L <sub>eff</sub>	2.5	2.0	$\mu$ m
Xj	0.35	0.62	$\mu$ m
Rs	27	41	$\Omega$ /square
Rs poly1	20	27	$\Omega$ /square
Rs poly2	28	—	$\Omega$ /square